

RoHS Compliant Product  
A suffix of "-C" specifies halogen & lead-free

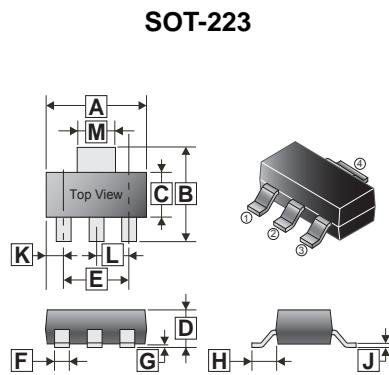
## DESCRIPTION

The SSM0410S provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness. The SOT-223 package is universally preferred for all commercial-industrial surface mount applications and suited for low voltage applications such as DC/DC converters.

## FEATURES

- Lower Gate Charge
- Simple Drive Requirement
- Fast Switching Characteristic

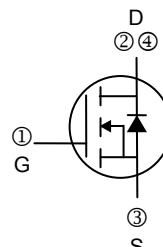
## MARKING



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	6.20	6.70	G	-	0.10
B	6.70	7.30	H	-	-
C	3.30	3.70	J	0.25	0.35
D	1.42	1.90	K	-	-
E	4.50	4.70	L	2.30	REF.
F	0.60	0.82	M	2.90	3.10

## PACKAGE INFORMATION

Package	MPQ	Leader Size
SOT-223	2.5K	13 inch



## ABSOLUTE MAXIMUM RATINGS (T<sub>A</sub>=25°C unless otherwise specified)

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V <sub>DS</sub>	100	V
Gate-Source Voltage	V <sub>GS</sub>	±20	V
Continuous Drain Current <sup>1</sup> @V <sub>GS</sub> =10V	I <sub>D</sub>	3	A
		1.7	A
Pulsed Drain Current <sup>2</sup>	I <sub>DM</sub>	5.5	A
Power Dissipation <sup>3</sup>	P <sub>D</sub>	1.5	W
Operating Junction & Storage Temperature	T <sub>J</sub> , T <sub>STG</sub>	-65~150	°C
Thermal Resistance Rating			
Thermal Resistance Junction-Ambient <sup>1</sup> (Max).	R <sub>θJA</sub>	85	°C / W
Thermal Resistance Junction-Case <sup>1</sup> (Max).	R <sub>θJC</sub>	36	°C / W

**ELECTRICAL CHARACTERISTICS** ( $T_J = 25^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
<b>Static</b>						
Drain-Source Breakdown Voltage	$\text{BV}_{\text{DSS}}$	100	-	-	V	$\text{V}_{\text{GS}}=0$ , $\text{I}_D=250\mu\text{A}$
Gate-Threshold Voltage	$\text{V}_{\text{GS(th)}}$	1	-	2.5	V	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}$ , $\text{I}_D=250\mu\text{A}$
Forward Transconductance	$\text{g}_{\text{fs}}$	-	4	-	S	$\text{V}_{\text{DS}}=5\text{V}$ , $\text{I}_D=2\text{A}$
Gate-Source Leakage Current	$\text{I}_{\text{GSS}}$	-	-	$\pm 100$	nA	$\text{V}_{\text{GS}}= \pm 20\text{V}$
Drain-Source Leakage Current	$\text{I}_{\text{DSS}}$	-	-	1	$\mu\text{A}$	$\text{V}_{\text{DS}}=80\text{V}$ , $\text{V}_{\text{GS}}=0$ , $T_J=25^\circ\text{C}$
		-	-	5		$\text{V}_{\text{DS}}=80\text{V}$ , $\text{V}_{\text{GS}}=0$ , $T_J=55^\circ\text{C}$
Static Drain-Source On-Resistance <sup>2</sup>	$\text{R}_{\text{DS(ON)}}$	-	-	310	$\text{m}\Omega$	$\text{V}_{\text{GS}}=10\text{V}$ , $\text{I}_D=3\text{A}$
		-	-	320		$\text{V}_{\text{GS}}=4.5\text{V}$ , $\text{I}_D=1.7\text{A}$
Total Gate Charge(10V)	$\text{Q}_g$	-	9.1	-	nC	$\text{I}_D=2\text{A}$ $\text{V}_{\text{DS}}=50\text{V}$ $\text{V}_{\text{GS}}=10\text{V}$
Gate-Source Charge	$\text{Q}_{\text{gs}}$	-	2	-		
Gate-Drain Change	$\text{Q}_{\text{gd}}$	-	1.4	-		
Turn-on Delay Time <sup>2</sup>	$\text{T}_{\text{d(on)}}$	-	2	-	nS	$\text{V}_{\text{DD}}=50\text{V}$ $\text{I}_D=2\text{A}$ $\text{V}_{\text{GS}}=10\text{V}$ $\text{R}_G=3.3\Omega$ $\text{R}_L=30\Omega$
Rise Time	$\text{T}_r$	-	21.6	-		
Turn-off Delay Time	$\text{T}_{\text{d(off)}}$	-	11.2	-		
Fall Time	$\text{T}_f$	-	18.8	-		
Input Capacitance	$\text{C}_{\text{iss}}$	-	508	-	pF	$\text{V}_{\text{GS}}=0$ $\text{V}_{\text{DS}}=15\text{V}$ $f=1.0\text{MHz}$
Output Capacitance	$\text{C}_{\text{oss}}$	-	29	-		
Reverse Transfer Capacitance	$\text{C}_{\text{rss}}$	-	16.4	-		
<b>Source-Drain Diode</b>						
Diode Forward Voltage <sup>2</sup>	$\text{V}_{\text{SD}}$	-	-	1.2	V	$\text{I}_S=1\text{A}$ , $\text{V}_{\text{GS}}=0$ , $T_J=25^\circ\text{C}$
Continuous Source Current <sup>1,4</sup>	$\text{I}_S$	-	-	3	A	$\text{V}_D=\text{V}_G=0$ , Force Current
Pulsed Source Current <sup>2,4</sup>	$\text{I}_{\text{SM}}$	-	-	5.5	A	
Reverse Recovery Time	$\text{T}_{\text{rr}}$	-	17.5	-	nS	$\text{I}_F=2\text{A}$ , $d\text{I}/dt=100\text{A}/\mu\text{s}$ , $T_J=25^\circ\text{C}$
Reverse Recovery Charge	$\text{Q}_{\text{rr}}$	-	14	-	nC	

Note:

1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2oz copper.
2. The data tested by pulsed , pulse width  $\leq 300\mu\text{s}$  , duty cycle  $\leq 2\%$
3. The power dissipation is limited by  $150^\circ\text{C}$ , junction temperature.
4. The data is theoretically the same as  $\text{I}_D$  and  $\text{I}_{\text{DM}}$  , in real applications , should be limited by total power dissipation.

## CHARACTERISTIC CURVES

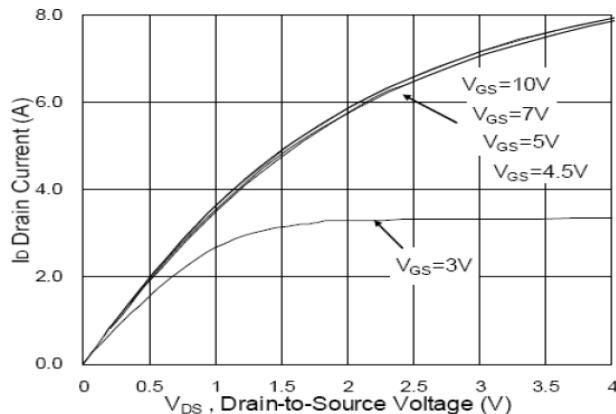


Fig.1 Typical Output Characteristics

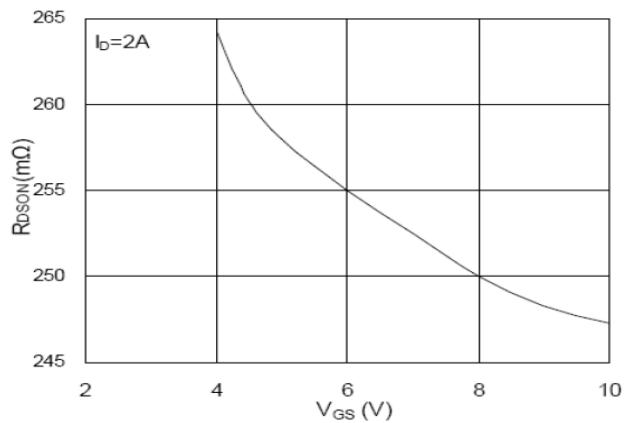


Fig.2 On-Resistance vs. Gate-Source

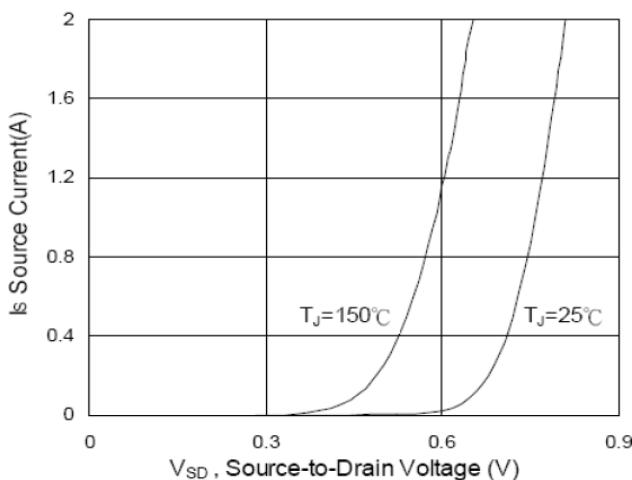


Fig.3 Forward Characteristics of Reverse

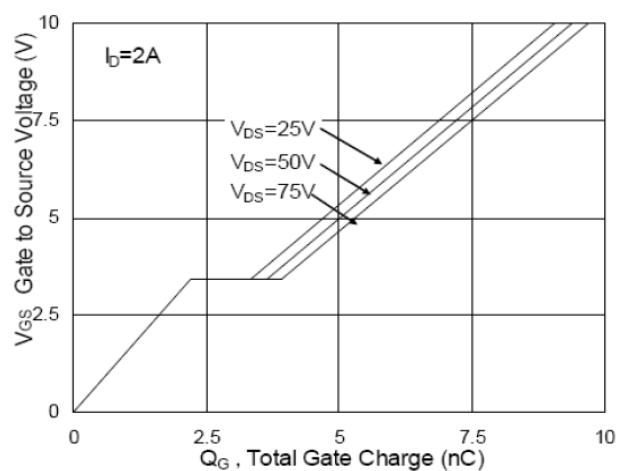


Fig.4 Gate-Charge Characteristics

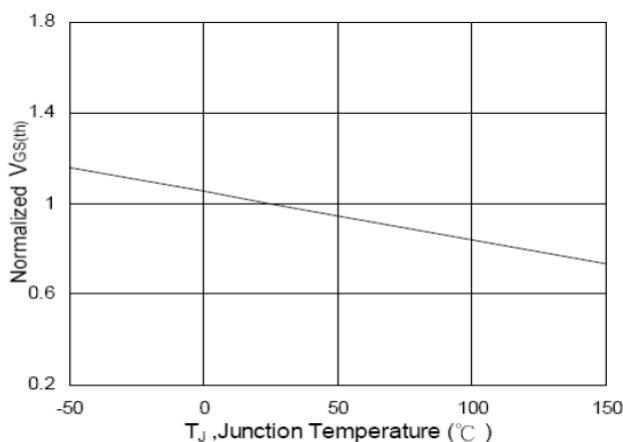


Fig.5 Normalized  $V_{GS(th)}$  vs.  $T_J$

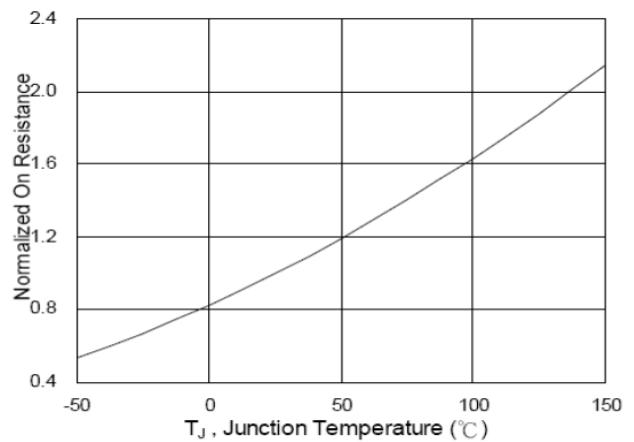


Fig.6 Normalized  $R_{DS(on)}$  vs.  $T_J$

## CHARACTERISTIC CURVES

